

*Rapid fire*

# Fast Timing MPGD

**INFN Workshop on Future Detectors (IFD)**

October 18th 2022

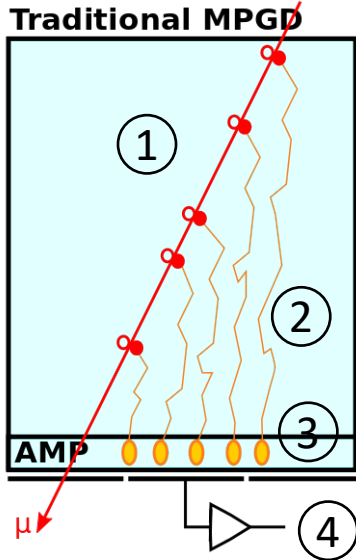
Piet Verwilligen – INFN Bari

Antonello Pellecchia, Marcello Maggi & many others ....

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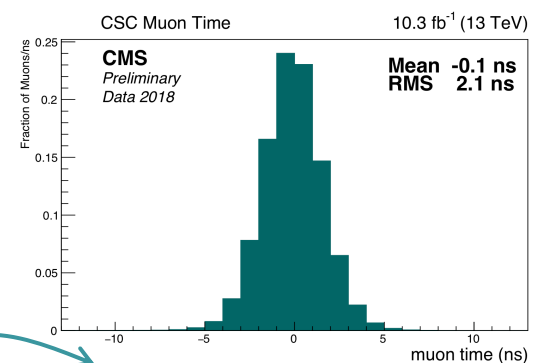
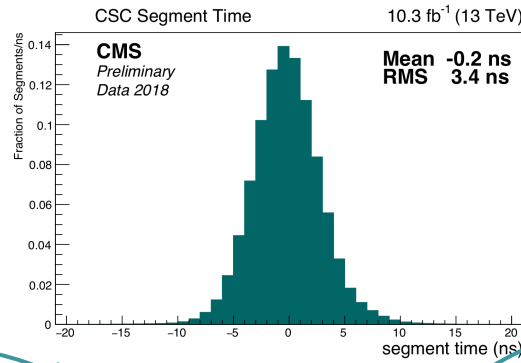
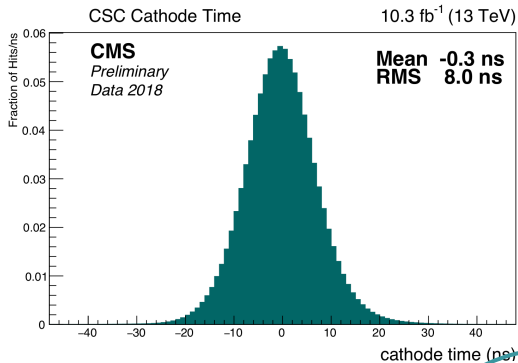
# Timing with Gaseous Detectors in Proportional Mode (wires, MPGDs)



- with primary electron creation in gas (“Primary Ionization”) typically in a so-called “Drift Volume” is limited to 5-10ns [1]
- Independent of Electric Field: parallel or circular wire detector
- Time resolution limited due to fluctuations in primary ionization
- Typical Fluctuation of closest primary electron to amplification structure. Example: Triple-GEM in **Ar:CO<sub>2</sub> (70:30)**  $\lambda \sim 2.8\text{mm}^{-1}$   
 $\langle d \rangle = 350\mu\text{m}$ ,  $v_{\text{drift}} = 70\mu\text{m/ns}$  (3kV/cm)  $\rightarrow \sigma_t^{\text{primaries}} = 5\text{ ns}$  (1)
- Next factors that influence time resolution in these detectors are:
  - Long diffusion flucts:  $\sigma_t^{\text{drift}} = \text{few } 10\text{s} - \text{few } 100\text{ ps}$  (2)
  - Avalanche flucts:  $\sigma_t^{\text{avalanche}} = \text{few } 10\text{s} - \text{few } 100\text{ps}$  (3)
  - Electronics jitter, system time distribution, start time,... (4)

Better time resolution obtained:  $\sigma_t / \sqrt{N}$

Example at LHC: CMS CSC



Single-hit  $\sigma_t = 8\text{ns}$

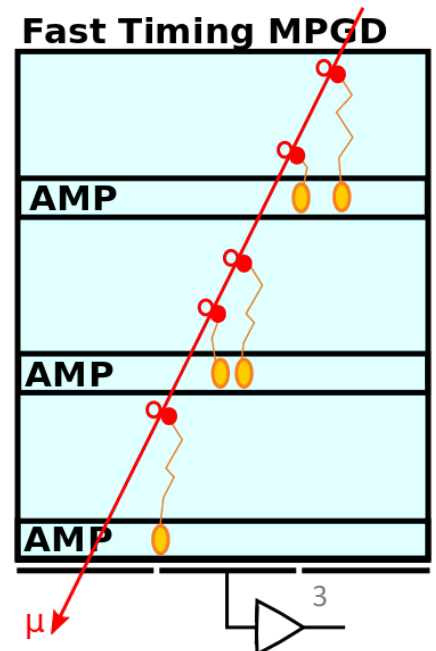
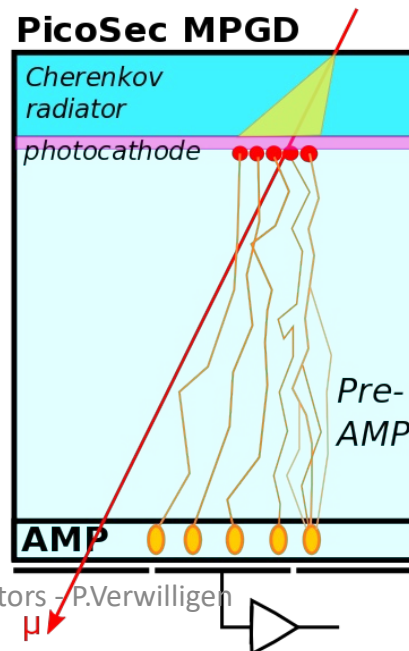
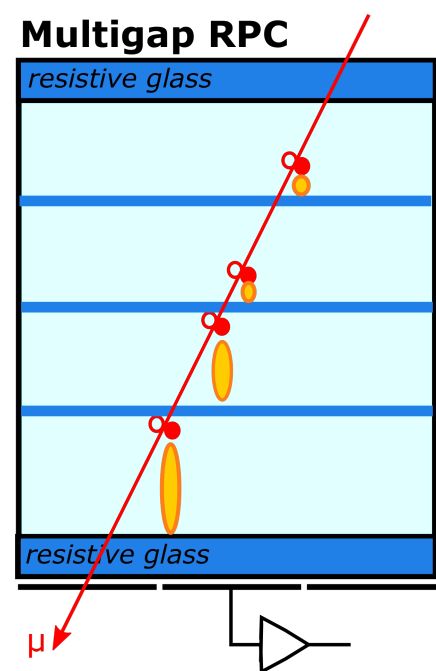
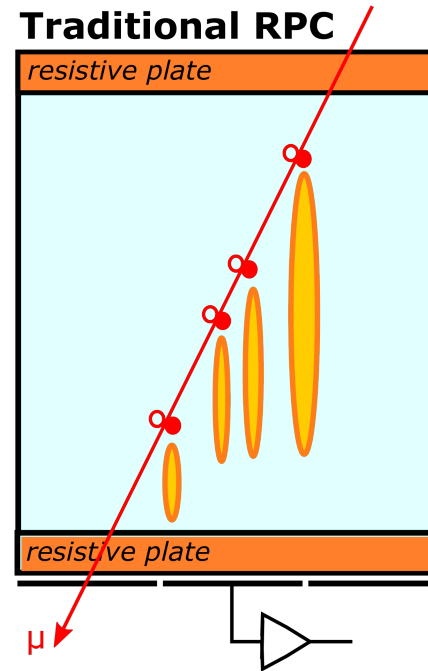
6-hit stub  $\sigma_t = 3.4\text{ns}$

4-stub muon  $\sigma_t = 2.1\text{ns}$

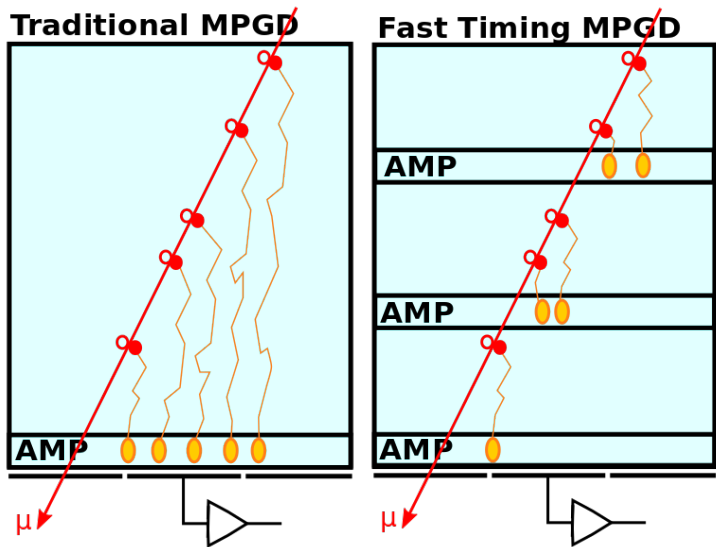
# Overcome limits time-resolution

## Possible Solutions:

- No drift volume, amplify immediately:  
**Resistive Plate Chamber** (2ns – 300ps)  
- at cost of loss of Proportionality,  
reduced Rate Capability &  $\sigma_x$
- Reduce gap width with order of  
magnitude and use multiple gaps:  
**Multigap-RPC** (100ps – 20ps)  
- same as RPC, but difficult for large area
- Create all primary electrons at same  
place (use Radiator+PC): **PicoSec** (<25ps)  
- but expensive radiators (Quartz, MgF2)  
& non rad-hard photo-cathodes (CsI)
- Sample the fluctuations in primary  
electron creation: **Fast Timing MPGD**  
(~300ps – not proven yet)  
- resistive MPGD: spark protection  
but reduced rate capability



# Fast Timing with MPGDs: FTM

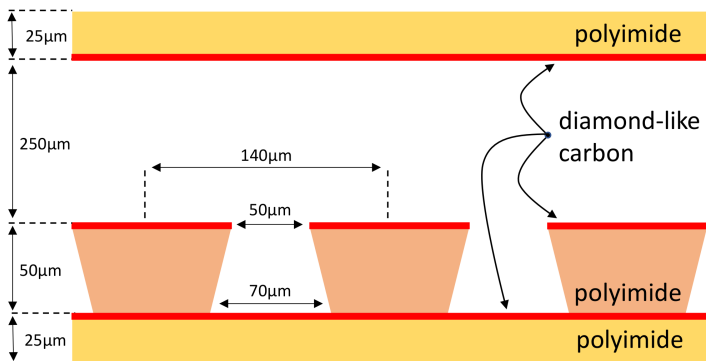


## Fast Timing MPGD (FTM): Principle

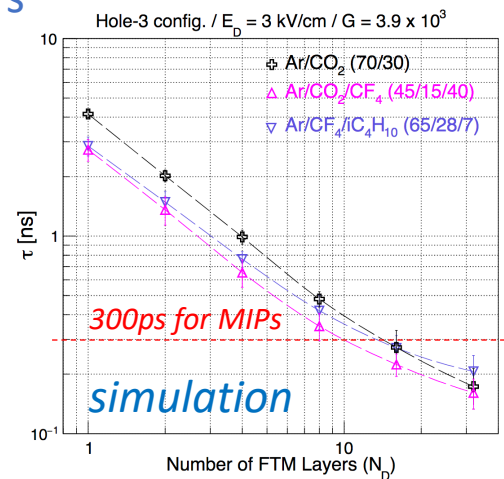
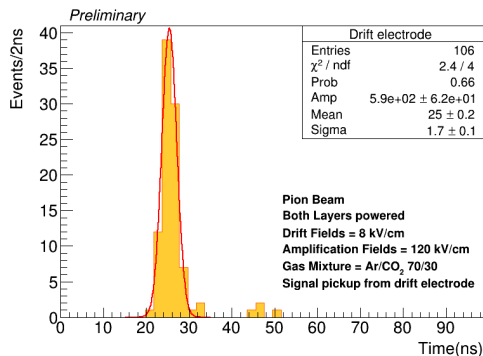
- Divide drift in multiple layers, each w/ own Amplification
- Resistive electrodes => Electrode Transparency
- Signal induced in External Pick-Up strips
- Closest primary electron => Fastest Signal
- Time Resolution  $\sigma_t = 1/(\lambda \cdot v_{drift} \cdot N)$ , where  $N = \text{layers}$
- Observed: 2ns with 2 layer detector [4] ( $\rightarrow$  OK)

## Fast Timing MPGD: Challenges:

- Detect single-electron (or single cluster) instead of many clusters
- **Requires High Gain Structures**
- **Requires sensitive front-end electronics**



## Test Beam Results (2 layers)



References:

- [1] F.Sauli, Yellow Report, CERN-77-09 (1977)
- [2] P.Verwilligen *et al.* J.Phys.Conf.Ser. 1498 (2020)
- [3] M.Maggi *et al.* arXiv:1503.05330 (2015)
- [4] I.Vai *et al.* NIM A 845 (2017) 313

# FTM: Technological Challenges

## Single gain structure capable of gain > 10<sup>4</sup>

- with non-greenhouse, non-GWP, non-flammable gas
- Main Challenge: production of high quality Amplification foils
  - Requires well adherent 2-sided Cu-DLC foils
  - CERN – INFN DLC Sputter machine is coming
  - In past years: collaboration with solid state physicist (INFN CSN-V)
    - High quality DLC production on small size prototypes 1-50cm<sup>2</sup>
    - Strategies pioneered small scale can be brought to large scale production
- Side: understand details of capacitive signal induction in readout (first time for small Q)
- Future: 125um well height – Plasma Etching

⇒ Require technological advancements to make high quality detectors

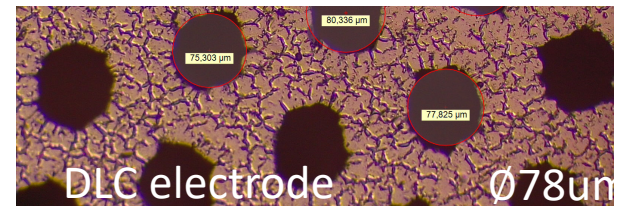
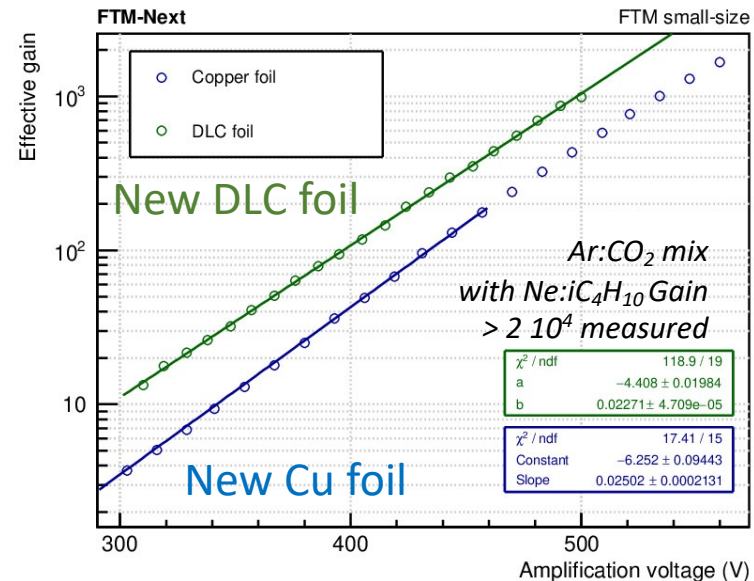
## Development of Fast and Sensitive electronics

Single-Stage MPGD have typical gain of  $3 \cdot 10^3$  – max  $10^4$ .  
Assume signal not dispersed over strips, signals of 0.5-1fC

Fast Timing typically done for large signals:

$$\sigma_t = \sigma_{\text{noise}} / dV/dt = t_{\text{rise}} / \text{SNR}$$

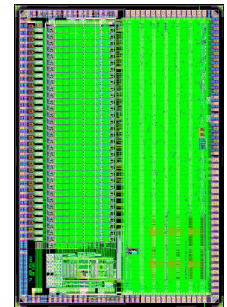
⇒ Now bring fast timing to smaller signals. Need very low noise amplifiers



## FATIC (130nm Si CMOS)

- 32 channels + 1 test
- Gain: 10mV/fC & 50mV/fC
- ENC: 500e<sup>-</sup> @ 15pF
- Rise time: 7.5ns
- Analog: time & Charge
- Digital: TDC (100ps)

Want to develop new version in:



Backup

